

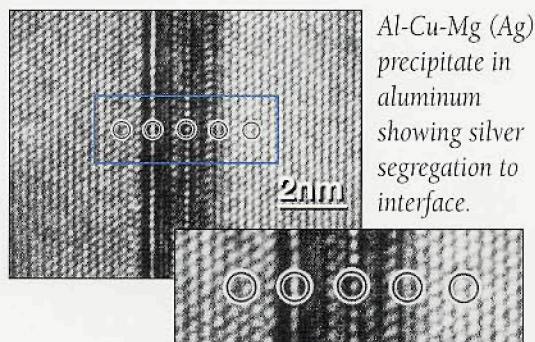
# Sights Unseen.

With the New JEM-2010F Field Emission Electron Microscope  
You'll See It ... If It's There.

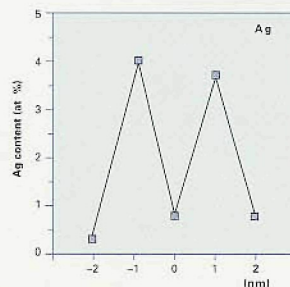
From JEOL...the newest generation of precision equipment that permits unprecedented resolution in 3-dimensional, subnanometer analysis of microstructures. Featuring user-friendly operation and long-term stability, the JEM-2010F also offers:

- Schottky Emission: High Current High Brightness
- High Probe Current: 0.5nm Probe with 100 pA Current
- High Resolution: Information Limit 1.4Å, Scherzer 1.9Å
- Holography: Option Available
- STEM Resolution: 0.2nm Magnification: 8MX

Discover the JEM-2010F and visit sights previously unseen.



Al-Cu-Mg (Ag) precipitate in aluminum showing silver segregation to interface.



Data courtesy of Dr. James M. Howe, Department of Materials Science & Engineering, University of Virginia, U.S.A.



JEOL USA, Inc., 11 Dearborn Road, Peabody, MA 01960  
Tel: 508-535-5900 Fax: 508-536-2205 e-mail: eod@jeol.com

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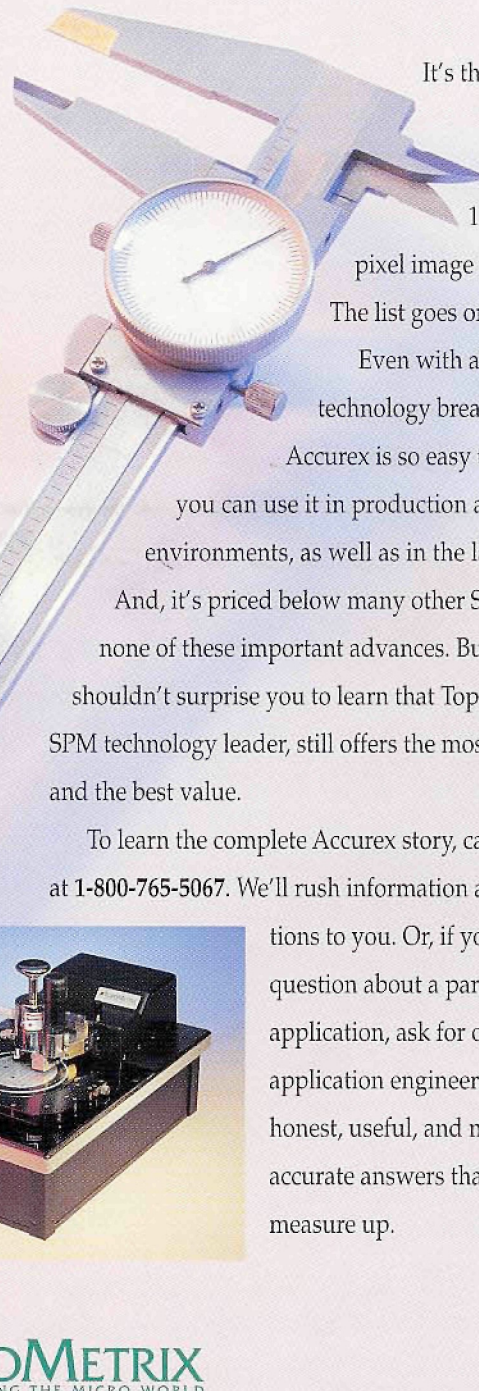
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A machinist's caliper isn't very useful without an accurate, calibrated scale. That's not much different than a scanning probe microscope without a calibrated Z.

Introducing Accurex.™ A new family of SPMs from TopoMetrix.

Accurex does away with performance compromises. It features TrueMetrix,™ TopoMetrix' proprietary closed-loop scanner linearization system that uses inherently linear sensors to guarantee accurate X, Y and Z measurements.

But Accurex gives you a lot more. It scans in the broadest spectrum of both contact and non-contact scanning modes. Not just one. Or a select few. But virtually every conventional mode. What's more, it's available with a choice of sample stages that can handle samples up to 14 inches in diameter, four inches thick. And, Accurex features the industry's most advanced software, SPMLab.™



It's the only commercial SPM software with 1,000 x 1,000 pixel image resolution.

The list goes on.

Even with all these technology breakthroughs,

Accurex is so easy to operate you can use it in production and process environments, as well as in the laboratory.

And, it's priced below many other SPMs that offer none of these important advances. But then, it shouldn't surprise you to learn that TopoMetrix, the SPM technology leader, still offers the most innovations and the best value.

To learn the complete Accurex story, call us today at 1-800-765-5067. We'll rush information and specifica-

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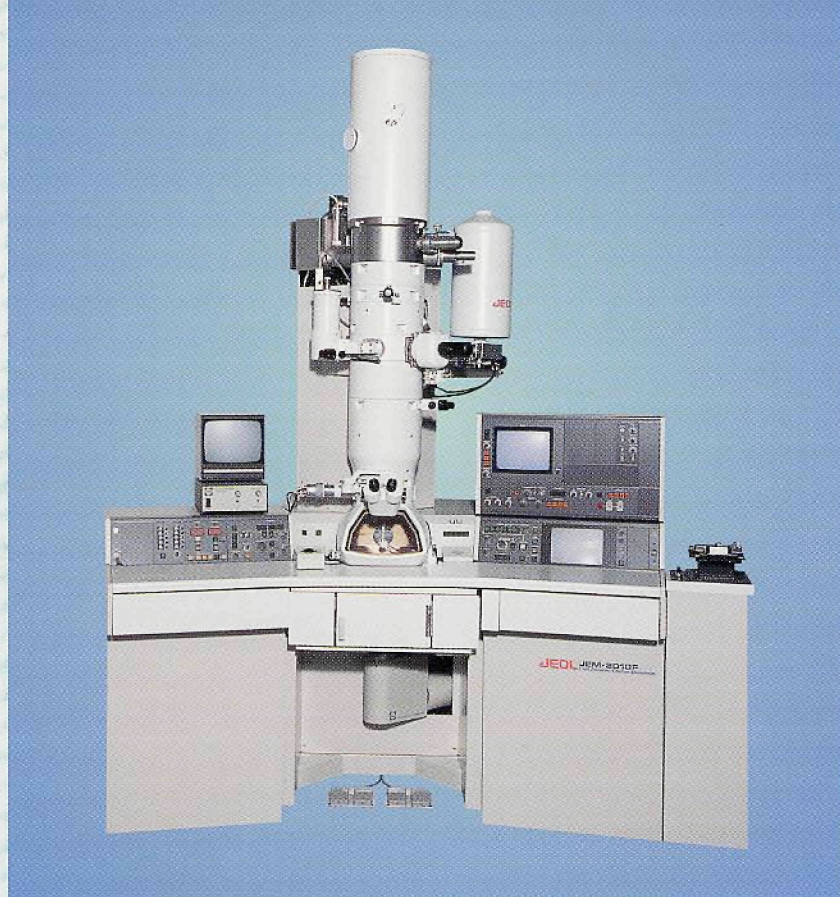


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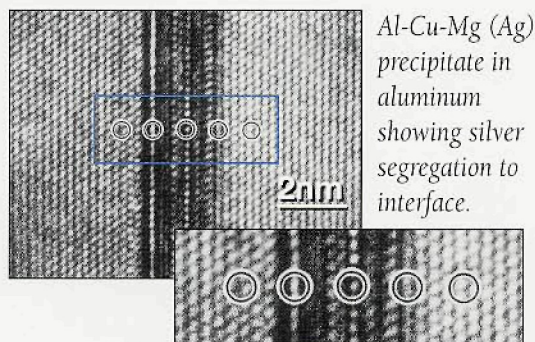
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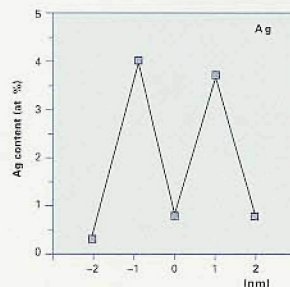
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